



JAPANESE  
INDUSTRIAL  
STANDARD

Translated and Published by  
Japanese Standards Association

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JIS C 6701 : 2021

(JSA)

**Generic specification and test methods of  
quartz crystal units**

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ICS 31.140

Reference number : JIS C 6701 : 2021 (E)

C 6701 : 2021

Date of Establishment: 1960-07-01

Date of Revision: 2021-03-22

Date of Public Notice in Official Gazette: 2021-03-22

Developed by: Japanese Standards Association

Investigated by: JIS Development Committee on Electronics

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JIS C 6701 : 2021, First English edition published in 2023-01

Translated and published by: Japanese Standards Association  
Mita MT Building, 3-13-12, Mita, Minato-ku, Tokyo, 108-0073 JAPAN

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In the event of any doubts arising as to the contents,  
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Printed in Japan

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## Contents

	Page
Introduction .....	1
1 Scope .....	1
2 Normative references .....	1
3 Terms and definitions .....	4
3.1 General .....	4
3.2 Terms and definitions .....	4
4 General requirements .....	19
4.1 Preferred ratings and characteristics .....	19
4.2 Marking .....	21
5 Quality assessment procedures .....	22
5.1 General .....	22
5.2 Primary stage of manufacture .....	22
5.3 Structurally similar components .....	22
5.4 Subcontracting .....	22
5.5 Manufacturer's approval .....	23
5.6 Approval procedures .....	23
5.7 Procedures for capability approval .....	23
5.8 Procedures for qualification approval .....	24
5.9 Test procedures .....	24
5.10 Screening requirements .....	25
5.11 Rework and repair work .....	25
5.12 Certified records of released lots .....	25
5.13 Validity of release .....	25
5.14 Release for delivery .....	25
5.15 Unchecked parameters .....	25
6 Test and measurement procedures .....	26
6.1 General .....	26
6.2 Alternative test methods .....	26
6.3 Precision of measurement .....	26
6.4 Standard conditions for testing .....	26
6.5 Visual inspection .....	26
6.6 Dimensioning and gauging procedures .....	27
6.7 Electrical test procedures .....	27
6.8 Mechanical and environmental test procedures .....	29
6.9 Endurance test procedure .....	34
Annex A (normative) Experimental verification of frequency aging perfor-	

	mance .....	39
Annex JA (informative)	Basic method for measurement of resonance frequency and equivalent resistance of quartz crystal units by zero phase technique in $\pi$ -network .....	41
Annex JB (informative)	Methods for determination of equivalent electrical parameters using automatic network analyser techniques and error correction .....	43
Annex JC (informative)	Measuring method of drive level dependency .....	49
Annex JD (informative)	Measurement of activity and frequency dips of crystal units .....	52
Annex JE (informative)	Terminology related to crystal units .....	56
Annex JF (informative)	Comparison table between JIS and corresponding International Standard .....	59

## Foreword

This Japanese Industrial Standard has been revised by the Minister of Economy, Trade and Industry based on the provision of Article 14, paragraph (1) of the Industrial Standardization Act applied mutatis mutandis pursuant to the provision of Article 16 of the said Act in response to a proposal for revision of Japanese Industrial Standard with a draft being attached, submitted by Japanese Standards Association (JSA), an accredited standards development organization. This edition replaces the previous edition (**JIS C 6701** : 2007), which has been technically revised.

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# Generic specification and test methods of quartz crystal units

## Introduction

This Japanese Industrial Standard has been prepared based on **IEC 60122-1** : 2002, Edition 3, and Amendment 1 : 2017 with some modifications of the technical contents to correspond to the actual situations in Japan. The amendment to the said International Standard has been incorporated into this Standard.

Annex JA to Annex JE are unique to **JIS** and not given in the corresponding International Standard. The dotted underlines indicate changes from the corresponding International Standard. A list of modifications with the explanations is given in Annex JF.

## 1 Scope

This Standard specifies the methods of test and general requirements for quartz crystal units of assessed quality using either capability approval and/or qualification approval procedures.

NOTE 1 Where any discrepancies occur for any reason, documents may rank in the following order of precedence :

- the detail specifications;
- the sectional specification;
- the generic specification;
- any other international documents (e.g. **IEC**) to which reference is made.

**NOTE 2** The International Standard corresponding to this Standard and the symbol of degree of correspondence are as follows.

**IEC 60122-1** : 2002 *Quartz crystal units of assessed quality — Part 1 : Generic specification* + Amendment 1 : 2017 (MOD)

In addition, symbols which denote the degree of correspondence in the contents between the relevant International Standard and **JIS** are IDT (identical), MOD (modified), and NEQ (not equivalent) according to **ISO/IEC Guide 21-1**.

## 2 Normative references

Part or all of the provisions of the following standards, through reference in this text, constitute provisions of this Standard. For standards indicated below, only the editions of the indicated year shall be applied and any revisions (including amendments) made thereafter shall not be applied.

**JIS C 60068-1** : 2016 *Environmental testing — Part 1 : General and guidance*